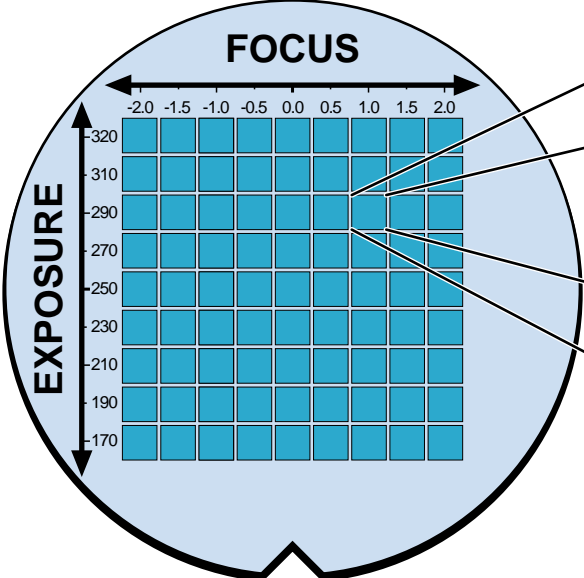
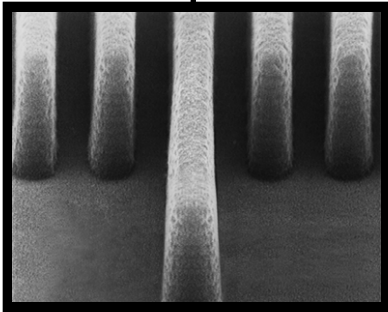
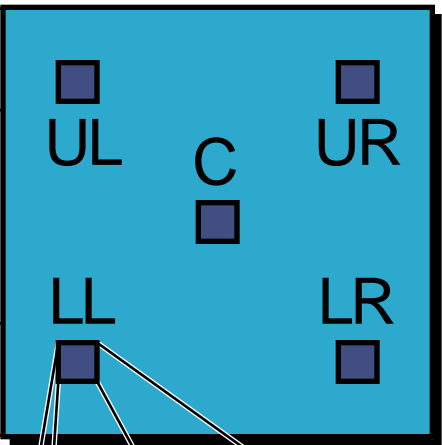


FOCUS-EXPOSURE TEST WAFER

FOCUS-EXPOSURE GRID



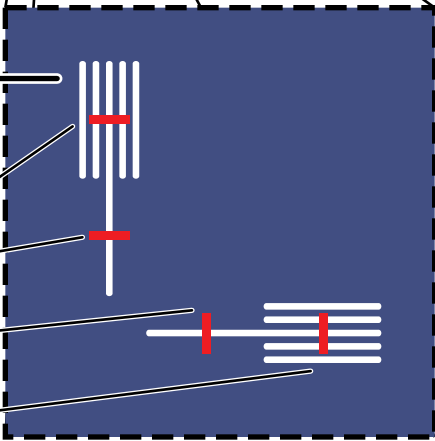
SAMPLE SITES



50,000X SEM photo

TEST STRUCTURE

- X-DENSE
- X-ISO
- Y-ISO
- Y-DENSE



MEASUREMENT AREAS